

May 2014

FDMS7620S

Dual N-Channel PowerTrench[®] MOSFET Q1: 30 V, 13 A, 20.0 m Ω Q2: 30 V, 22 A, 11.2 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 20.0 m Ω at V_{GS} = 10 V, I_D = 10.1 A
- Max $r_{DS(on)}$ = 30.0 m Ω at V_{GS} = 4.5 V, I_D = 7.5 A

Q2: N-Channel

- Max $r_{DS(on)}$ = 11.2 m Ω at V_{GS} = 10 V, I_D = 12.4 A
- Max $r_{DS(on)}$ = 14.2 m Ω at V_{GS} = 4.5 V, I_D = 10.9 A
- Pinout optimized for simple PCB design
- Thermally efficient dual Power 56 Package
- RoHS Compliant



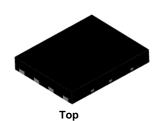
General Description

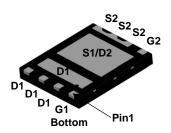
This device includes two specialized MOSFETs in a unique dual Power 56 package. It is designed to provide an optimal synchronous buck power stage in terms of efficiency and PCB utilization. The low switching loss "High Side" MOSFET is complementory by a low conduction loss "Low Side" SyncFET.

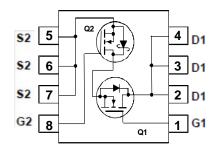
Applications

Synchronous Buck Converter for:

- Notebook System Power
- General Purpose Point of Load







Power 56

MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V _{DS}	Drain to Source Voltage		30	30	V
V_{GS}	Gate to Source Voltage	(Note 3)	±20	±20	V
	Drain Current -Continuous	T _C = 25 °C	13	22	
I _D	-Continuous T _A = 25 °C		10.1	12.4	Α
	-Pulsed		27	45	
E _{AS}	Single Pulse Avalanche Energy	Single Pulse Avalanche Energy (Note 4)		21	mJ
D	Power Dissipation for Single Operation	T _A = 25°C	2.2 ^{1a}	2.5 ^{1b}	W
P_{D}	Power Dissipation for Single Operation $T_A = 25^{\circ}C$		1.0 ^{1c}	1.0 ^{1d}	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 to	+150	°C	

Thermal Characteristics

I	$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	57 ^{1a}	50 ^{1b}	°C/W
I	$R_{ heta JA}$	Thermal Resistance, Junction to Ambient	125 ^{1c}	120 ^{1d}	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7620S	FDMS7620S	Power 56	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Chara	octeristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = 1 \text{ mA}, V_{GS} = 0 V$	Q1 Q2	30 30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25°C I_D = 10 mA, referenced to 25°C	Q1 Q2		19 19		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q1 Q2			1 500	μА
I _{GSS}	Gate to Source Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V	Q1 Q2			100 100	nA nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 mA$	Q1 Q2	1.0 1.0	2.2 2.0	3.0 3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C $I_D = 10 \text{ mA}$, referenced to 25°C	Q1 Q2		-6 -5		mV/°C
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 10.1 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125^{\circ}\text{C}$	Q1		15.2 22.7 18.7	20.0 30.0 22.5	mO
		$V_{GS} = 10 \text{ V}, \ I_D = 12.4 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 10.9 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 12.4 \text{ A}, \ T_J = 125^{\circ}\text{C}$	Q2		8.3 10.5 8.9	11.2 14.2 15.1	mΩ
g _{FS}	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_D = 10.1 \text{ A}$ $V_{DD} = 5 \text{ V}, I_D = 12.4 \text{ A}$	Q1 Q2		22 53		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2		457 1050	608 1400	pF
C _{oss}	Output Capacitance		Q1 Q2		167 358	222 477	pF
C _{rss}	Reverse Transfer Capacitance		Q1 Q2		22 35	31 49	pF
R _g	Gate Resistance		Q1 Q2	0.2 0.2	1.6 1.2	4.4 3.5	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	Q1		Q1 Q2	5.2 6.6	10 14	ns
t _r	Rise Time	$V_{DD} = 15 \text{ V, } I_{D} = 10$	$V_{DD} = 15 \text{ V}, I_{D} = 10.1 \text{ A}, R_{GEN} = 6 \Omega$		1.2 1.8	10 10	ns
t _{d(off)}	Turn-Off Delay Time	Q2 V_{DD} = 15 V, I_{D} = 12.4 A, R_{GEN} = 6 Ω		Q1 Q2	11.9 17.4	22 32	ns
t _f	Fall Time			Q1 Q2	1.4 1.5	10 10	ns
Q _{g(TOT)}	Total Gate Charge	V _{GS} = 0V to 10 V	$V_{GS} = 0V \text{ to } 10 \text{ V}$ Q1 $V_{DD} = 15 \text{ V},$ $I_{D} = 10.1 \text{ A}$		7.2 15.6	11 23	nC
Q _{g(TOT)}	Total Gate Charge	V _{GS} = 0V to 5 V			3.8 7.9	6 12	nC
Q _{gs}	Gate to Source Charge	Q2 V _{DD} = 15 V, I _D = 12.4 A		Q1 Q2	1.6 3.2		nC
Q _{gd}	Gate to Drain "Miller" Charge			Q1 Q2	1.1 1.6		nC

Units

Max

Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter

	Drain-Source Diode Characteristics								
Ī	V_{SD}	Source-Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 10.1 A	(Note 2)	Q1		0.90	1.2	V
	VSD	Source-Drain Diode Torward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 12.4 \text{ A}$	(Note 2)	Q2		0.83	1.2	*
Ī		Doverno Dogovery Time	Q1		Q1		16	28	
	t _{rr} Reverse Recovery Time	$I_F = 10.1 \text{ A}, \text{ di/dt} = 100 \text{ A/s}$		Q2		18	32	ns	
	0	Reverse Recovery Charge	Q2		Q1		4	10	nC
	Q _{rr}	Reverse Recovery Charge	$I_F = 12.4 \text{ A}, \text{ di/dt} = 300 \text{ A/s}$		Q2		13	23	IIC

Test Conditions

Notes

Symbol

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 57 °C/W when mounted on a 1 in² pad of 2 oz copper

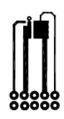


b. 50 °C/W when mounted on a 1 in² pad of 2 oz copper

Type

Min

Тур



c. 125 °C/W when mounted on a minimum pad of 2 oz copper



d. 120 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 $\,\mu s$, Duty cycle < 2.0%.
- 3. As an N-ch device, the negative Vgs rating is for low duty cycle pulse ocurrence only. No continuous rating is implied.
- 4. Q1: E_{AS} of 9 mJ is based on starting $T_J = 25$ ^{o}C , L = 0.3 mH, $I_{AS} = 8$ A, $V_{DD} = 27$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 12$ A. Q2: E_{AS} of 21 mJ is based on starting $T_J = 25$ ^{o}C , L = 0.3 mH, $I_{AS} = 12$ A, $V_{DD} = 27$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 18$ A.

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

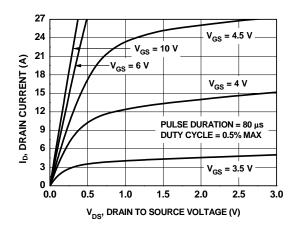


Figure 1. On Region Characteristics

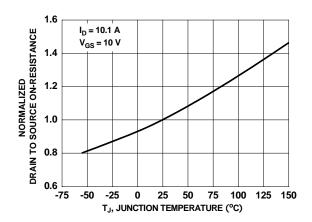


Figure 3. Normalized On Resistance vs Junction Temperature

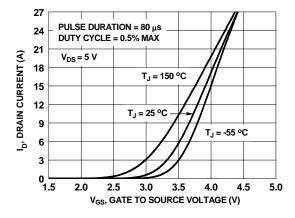


Figure 5. Transfer Characteristics

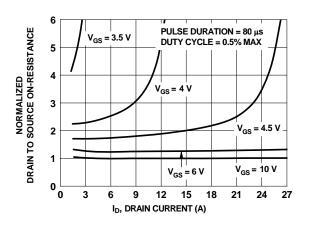


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

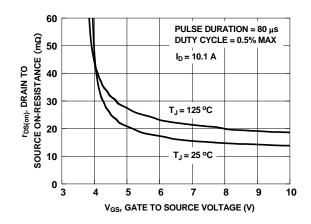


Figure 4. On-Resistance vs Gate to Source Voltage

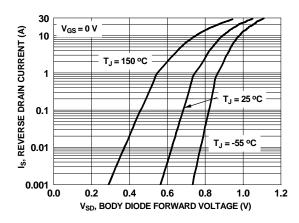


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25°C unless otherwise noted

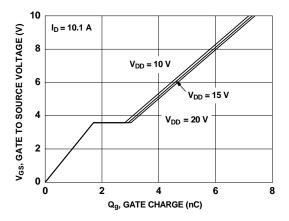


Figure 7. Gate Charge Characteristics

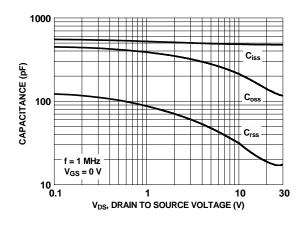


Figure 8. Capacitance vs Drain to Source Voltage

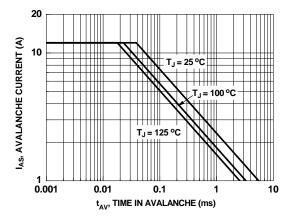


Figure 9. Unclamped Inductive Switching Capability

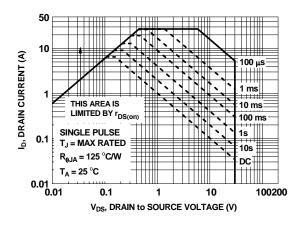


Figure 10. Forward Bias Safe Operating Area

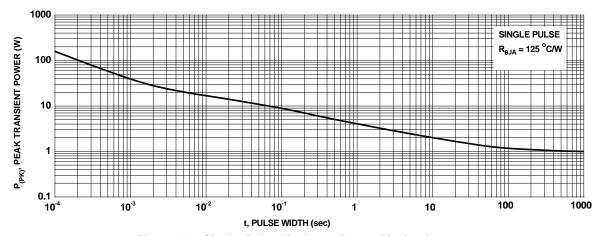


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) $T_J = 25$ °C unless otherwise noted

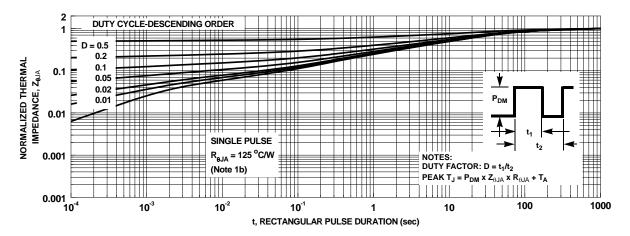


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unless otherwise noted

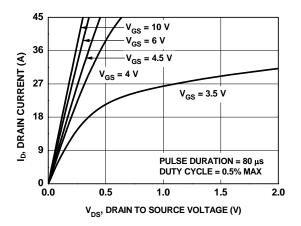


Figure 13. On-Region Characteristics

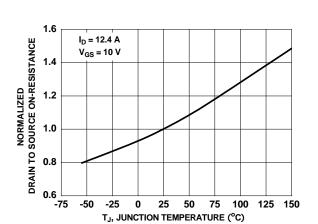


Figure 15. Normalized On-Resistance vs Junction Temperature

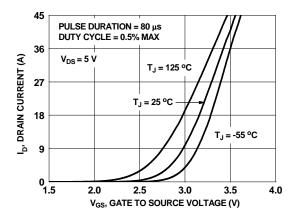


Figure 17. Transfer Characteristics

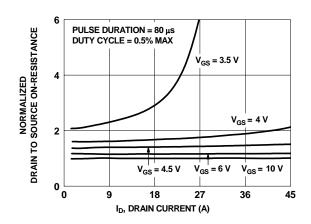


Figure 14. Normalized on-Resistance vs Drain Current and Gate Voltage

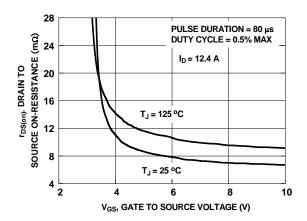


Figure 16. On-Resistance vs Gate to Source Voltage

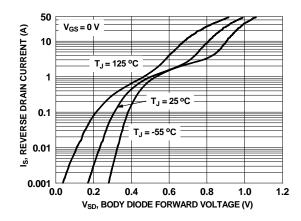


Figure 18. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 N-Channel) T_J = 25°C unless otherwise noted

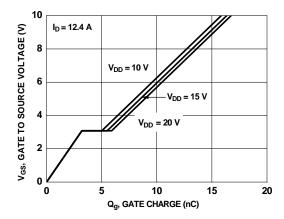


Figure 19. Gate Charge Characteristics

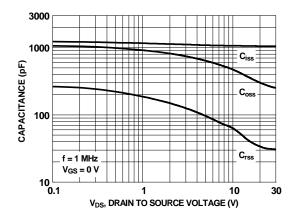


Figure 20. Capacitance vs Drain to Source Voltage

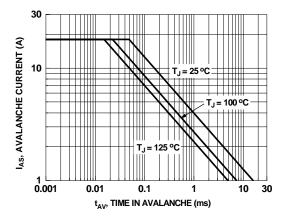


Figure 21. Unclamped Inductive Switching Capability

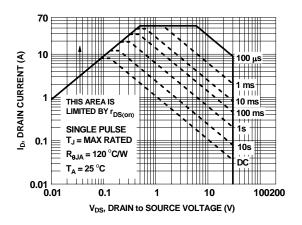


Figure 22. Forward Bias Safe Operating Area

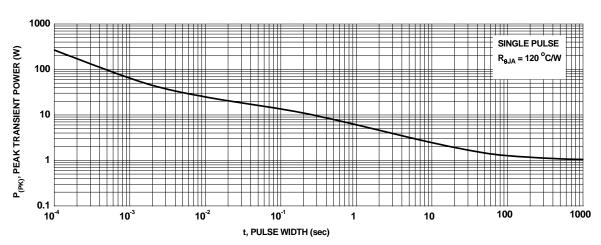


Figure 23. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 N-Channel) $T_J = 25$ °C unless otherwise noted

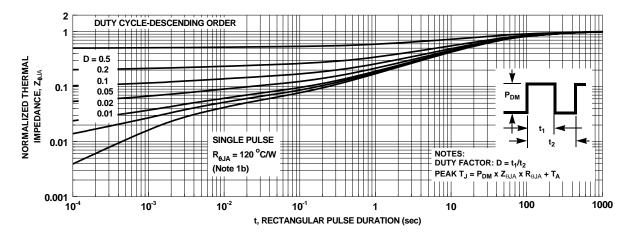


Figure 24. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFETTM Schottky body diode Characteristics

Fairchild's SyncFETTM process embeds a Schottky diode in parallel with PowerTrench[®] MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 26 shows the reverse recovery characteristic of the FDMS7620S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

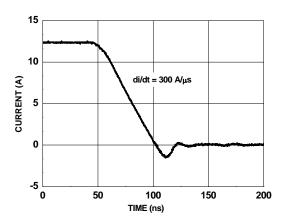


Figure 25. FDMS7620S SyncFET[™] Body Diode Reverse Recovery Characteristic

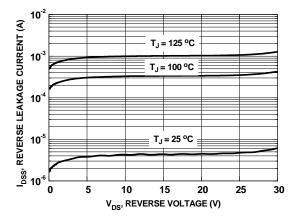
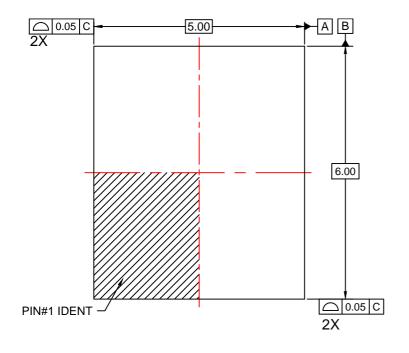
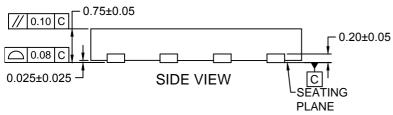
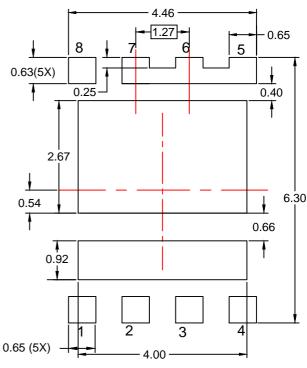


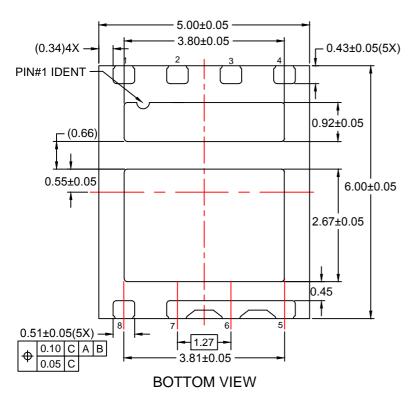
Figure 26. SyncFETTM Body Diode Reverse Leakage vs. Drain-Source Voltage





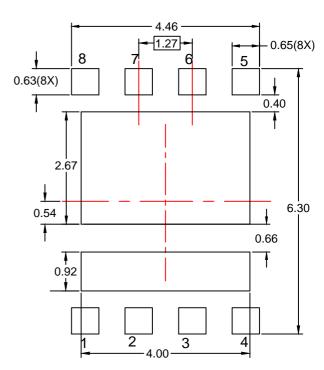


RECOMMENDED LAND PATTERN (OPTION 1 - FUSED LEADS 5,6,7)



NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC STANDARD.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Prev2.



RECOMMENDED LAND PATTERN (OPTION 2 - ISOLATED LEADS)







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PRODUCT STATUS DEFINITIONS

Definition of Terms

Definition of Terms		
Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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